

<b>Notice of References Cited</b>	Application/Control No. 10/692,622	Applicant(s)/Patent Under Reexamination VOGEDES ET AL.	
	Examiner <i>V. O</i> Kamran Afshar, 571-272-7796	Art Unit 2617	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,139,806	11-2006	Hayes et al.	709/207
*	B	US-6,993,364	01-2006	Sierawski et al.	455/567
*	C	US-7,039,428	05-2006	Helferich, Richard J.	455/458
*	D	US-6,999,731	02-2006	Cronin, Thomas M.	455/418
*	E	US-5,715,308	02-1998	Shankarappa, Vijay	379/373.02
*	F	US-2005/0245236	11-2005	Servi et al.	455/411
*	G	US-2006/0212585	09-2006	Eaton et al.	709/227
*	H	US-2005/0215272	09-2005	Helferich, Richard J.	455/512
*	I	US-2003/0052769	03-2003	Helferich, Richard J.	340/7.21
*	J	US-2003/0073450	04-2003	Laumen et al.	455/466
*	K	US-2003/0228866 A1	12-2003	Pezeshki, Farhad	455/422.1
*	L	US-2001/0019953	09-2001	Furukawa et al.	455/420
*	M	US-2004/0143636	07-2004	Horvitz et al.	709/207

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	11-046377	02-1999	JP	Momose Yashiro	H04Q 7/14
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.